

ABSTRACT

Test development tools, systems and/or methods which include accessing first and second pre-established test programs, each of said first and second pre-established test programs having been previously established for respective first and second pre-existing integrated circuit devices, and said first and second pre-established test programs each having respective first and second sets of subtest code portions; evaluating the first and second sets of subtest code portions and determining whether any respective subtest code portions of said first and second sets of subtest code portions have features allowing for combination in a new test program, said evaluating and determining steps providing at least one output result thereof; and defining a new test program including new subtest code portions for concurrently testing first and second pre-existing integrated circuit devices using the at least one output result of the evaluating and determining steps.